

512-BIT RECIRCULATING DYNAMIC SHIFT REGISTER (512X1) 1024-BIT RECIRCULATING DYNAMIC SHIFT REGISTER (1024X1)

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2524-N • 2525-N

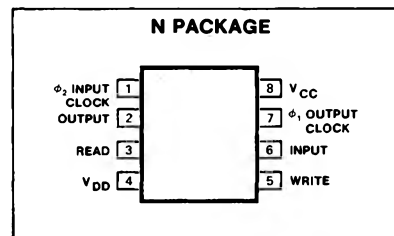
DESCRIPTION

The 2525 1024-bit recirculating dynamic shift register consists of enhancement mode p-channel MOS devices integrated on a single monolithic chip. Internal recirculation logic plus write and read controls are included on the chip.

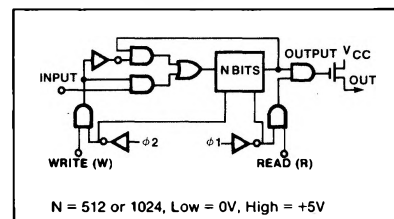
TRUTH TABLE

WRITE	READ	FUNCTION
0	0	Recirculate, Output is '0'
0	1	Recirculate, Output is data
1	0	Write mode, Output is '0'
1	1	Read mode, Output is data

PIN CONFIGURATION



BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS¹

PARAMETER	RATING	UNIT
T_A Temperature range ²	0 to 70	°C
T_{STG} Storage	-65 to 150	
P_D Power dissipation at $T_A > 70^\circ\text{C}^2$	535	mW
Data and clock input voltages and supply voltages with respect to V_{CC}	0.3 to -20	V

DC ELECTRICAL CHARACTERISTICS $T_A = 0^\circ\text{C}$ to 70°C , $V_{CC} = 5V \pm 5\%$, $V_{DD} = -5V \pm 5\%$ unless otherwise specified.

PARAMETER	TEST CONDITIONS	2524			2525			UNIT
		Min	Typ	Max	Min	Typ	Max	
V_{IL} Input voltage ³								V
V_{IH} Low		-5.0		0.6	-5.0		0.6	
V_{ILC} High		3.4		5.3	3.4		5.3	
V_{IHC} Clock low		-12.0		-10.0	-12.0		-10.0	
V_{IHC} Clock high		4.0		5.3	4.0		5.3	
V_{OL} Output voltage								V
V_{OH1} Low, driving 1 TTL load	$R_L = 3.0K$, 1 TTL load ($I_L = 1.6\text{mA}$) ⁴		-1.0			-1.0		
V_{OH2} High, driving 1 TTL load	$R_L = 3.0K$, 1 TTL load ($I_L = 100\mu\text{A}$)	2.4	3.5		2.4	3.5		
V_{OH2} High, driving MOS	$R_L = 5.6K$, $C_L = 10\text{pF}$	3.6	4.0		3.6	4.0		
I_{LI} Input load current	$V_{IN} = -5.5V$, $T_A = 25^\circ\text{C}$		10	500		10	500	nA
I_{LO} Leakage current	$T_A = 25^\circ\text{C}$							nA
I_{LC} Output	$V_{\phi 2} = V_{\phi 1} = -12V$, $V_{DD} = -5V$, $V_{OUT} = -5.5V$		10	1000		10	1000	
I_{LC} Clock	$V_{ILC} = -12V$		10	1000		10	1000	
I_{DD} Supply current	Continuous operation, $\phi\text{pW} = 150\text{ns}$, $f = 1\text{MHz}$, $V_{ILC} = -12V$, $T_A = 25^\circ\text{C}$, $V_{DD} = -5.5V$		15	35		25	35	mA
C_{IN} Capacitance	1MHz, $V_{AC} = 25\text{mV p-p}$							pF
C_{OUT} Input	$V_I = V_{CC}$			5			5	
C_ϕ Output	$V_O = V_{CC}$			5			5	
C_ϕ Clock	$V = V_{CC}$			80			160	

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AC ELECTRICAL CHARACTERISTICS

$T_A = 25^\circ\text{C}$, $V_{CC} = 5V \pm 5\%$, $V_{DD} = -5V \pm 5\%$, $V_{ILC} = -11V$,
Input rise and fall times = 10ns, Output load = 1 TTL gate

PARAMETER	TO	FROM	TEST CONDITIONS	LIMITS			UNIT
				Min	Typ	Max	
Freq. Clock data rep rate ⁵			$W = R = V_{CC}$.0005	5	3	MHz
$t_{\phi PW}$ Clock pulse width				135	85		ns
$t_{\phi D}$ Clock pulse delay				10			ns
$t_{R,F}$ Clock pulse transition				10		1000	ns
t_{DW} Setup and hold time							ns
t_{DH} Setup time	Clock	Data in		70			
t_{DH} Hold time	Data in	Clock		20			
t_{A+} Delay time	Data out	Clock				100	ns
$t_{R-,tw-}$ Clock to read or write timing				0			ns
$t_{R-,tw+}$ Clock to read or write timing				0			ns

NOTES

- Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a $+150^\circ\text{C}$ maximum junction temperature and a thermal resistance of 150°C/W junction to ambient.
- Guaranteed input levels are stated for worst case conditions including a $\pm 5\%$ variation in V_{CC} and a temperature variation of 0°C to $+70^\circ\text{C}$. Actual input requirements with respect to V_{CC} are $V_{IH} = V_{CC} - 1.85V$ and $V_{IL} = V_{CC} - 4.15V$.
- V_{OL} is a function of the input characteristics of the driven TTL/DTL gate I_{O1} and V_{CLAMP} and the value of the pull-down resistor (R_L).
- See Minimum Operating Frequency graph for low limits on data rep. rate.
- All inputs are protected against static charge.
- All voltage measurements are referenced to ground.
- Manufacturer reserving the right to make design and process changes and improvements.
- Typical values are at $+25^\circ\text{C}$ and typical supply voltages.
- Parameters are valid over operating temperature range unless otherwise specified.

TIMING DIAGRAM

